マイクロトモグラフィ用テストパターン 東海大 水谷研

Test patterns Mizutani Lab., Tokai Univ.

許可なく持ち出し禁止。

Not to be taken out without permission.

以下も参照のこと。

See also:

http://www.el.u-tokai.ac.jp/ryuta/patterns.htm



Test patterns, SPring-8 20B2 room

Normal

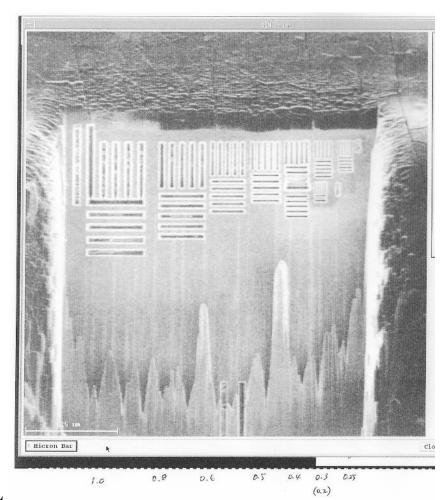
	id	Origin	Elem	Description
	080116AL	0.25 mmφ wire	Al	Pitch: 2.0, 1.6, 1.2, 1.0, 0.8, 0.6, 0.5, 0.4 um
	"Al test pattern"			"1.0 ~ 0.2 um"
	080425AL	0.25 mm ϕ wire	Al	Resin embed
				Pitch: 2.0, 1.6, 1.2, 1.0, 0.8, 0.6, 0.5, 0.4, 0.3, 0.2 um

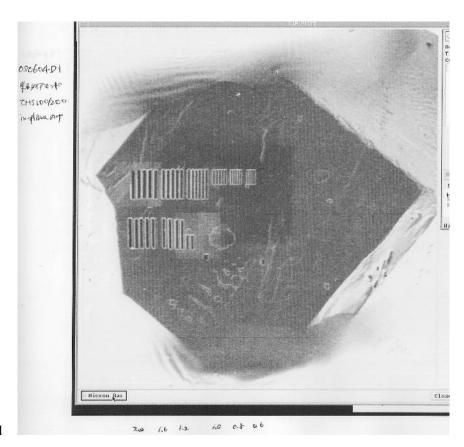
Nano

	121011AL	0.15 mm rod	Al	Resin embed
				Pitch: 2.0, 1.0, 0.5, 0.4, 0.3, 0.2, 0.18, 0.16, 0.14 um
	110906AL	0.1 x 0.1 mm rod	Al	Pitch: 1.0, 0.8, 0.6, 0.5, 0.4, 0.3, 0.2, 0.15 um
	130312AL	0.12 mm rod	Al	Pitch: 2.0, 1.0, 0.5 um,
				300, 240, 180, 140, 120, 100, 90 nm
	130315AL	0.10 mm rod	Al	Pitch: 2.0, 1.0, 0.5, 0.40, 0.35, 0.30, 0.25, 0.20 um,
				180, 160, 140, 120, 100, 90, 80 nm
	130524AL	0.10 mmφ wire	Al	Pitch: 2.0, 1.0, 0.5, 0.40, 0.35, 0.30, 0.25, 0.20 um,
				180, 160, 140, 120, 100, 90, 80 nm

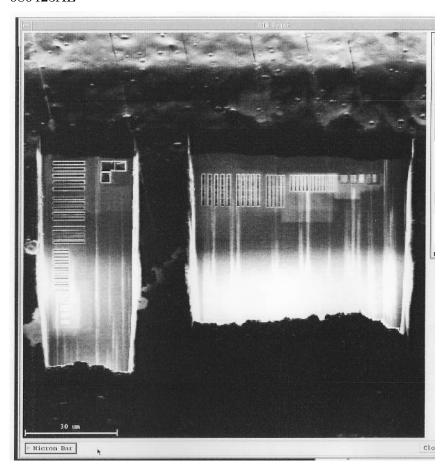
Diamond

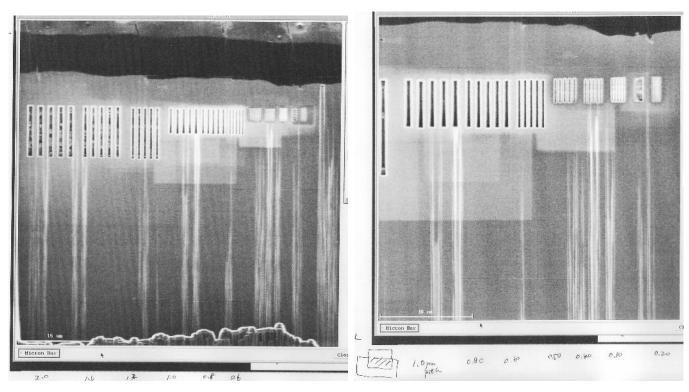
		080604D1		wire	Diamond	In-plane only; Pitch: 2.0, 1.6, 1.2, 1.0, 0.8, 0.6 um
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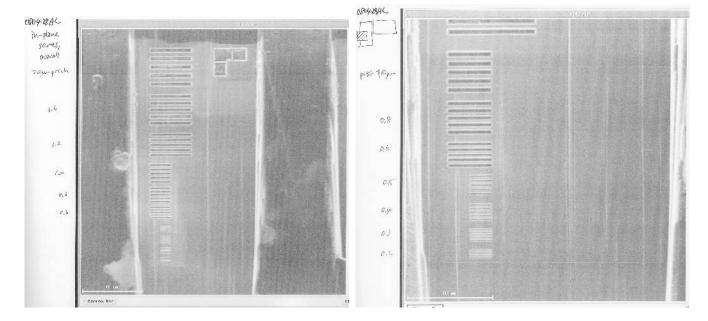


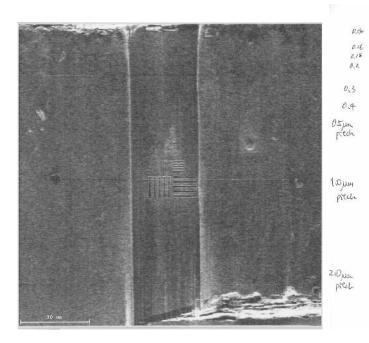
080604D1

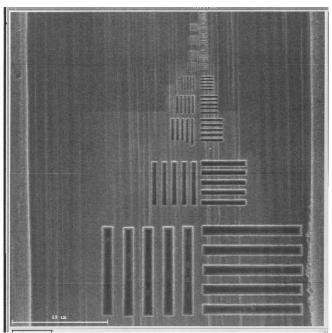


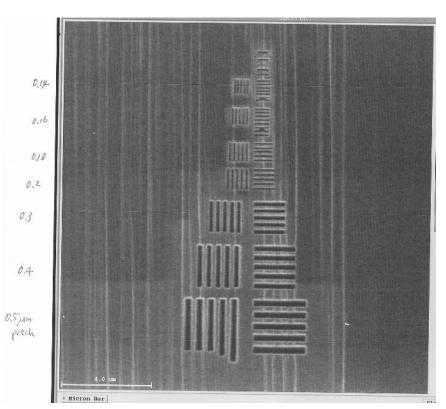


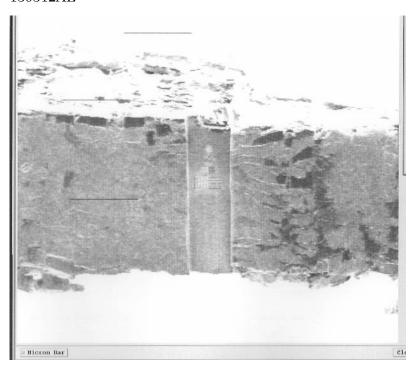
$080425\mathrm{AL}$











$130312\mathrm{AL}$

